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AKS	D		Charles Partee et al., "Off-Track Response Versus Shield Width at the ABS for MR Heads",														
			IEEE Transactions on Magnetics (USA), Vol. 33, No. 5, Pt. 1, Sept. 1997, pp. 2887-9.														
AICS	E		W.M. Kaminsky et al., "Patterning Ferromagnetism in Ni <sub>80</sub> Fe <sub>20</sub> Films via 30 keV Ga <sup>+</sup> on Irradiation", Applied Physics Letters, March 30 2000.														
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